

# RFS-R 3-2

Scanner Probe 30 MHz up to 3 GHz



## Short description

The RFS-R 3-2 scanner probe is used for the high-resolution measurement of RF magnetic fields directly on an assembly e.g. in range around pins and IC cases, conducting paths, decoupling capacitor and EMC components.

The RFS-R 3-2 is a passive near-field probe. The H-field probe is designed to be used very close to the components and where high magnetic field strength occurs. It has a current attenuating sheath and, therefore, is electrically shielded. The magnetic field scanner probe can be connected to a spectrum analyzer or an oscilloscope with a 50  $\Omega$  input. The H-field probe does not have an internal terminating resistance of 50  $\Omega$ .

## Technical parameters

Frequency range	30 MHz ... 3 GHz
Resolution	$\approx 1$ mm
Probe head dimensions	$\varnothing \approx 3$ mm
Connector - output	SMA, male, jack

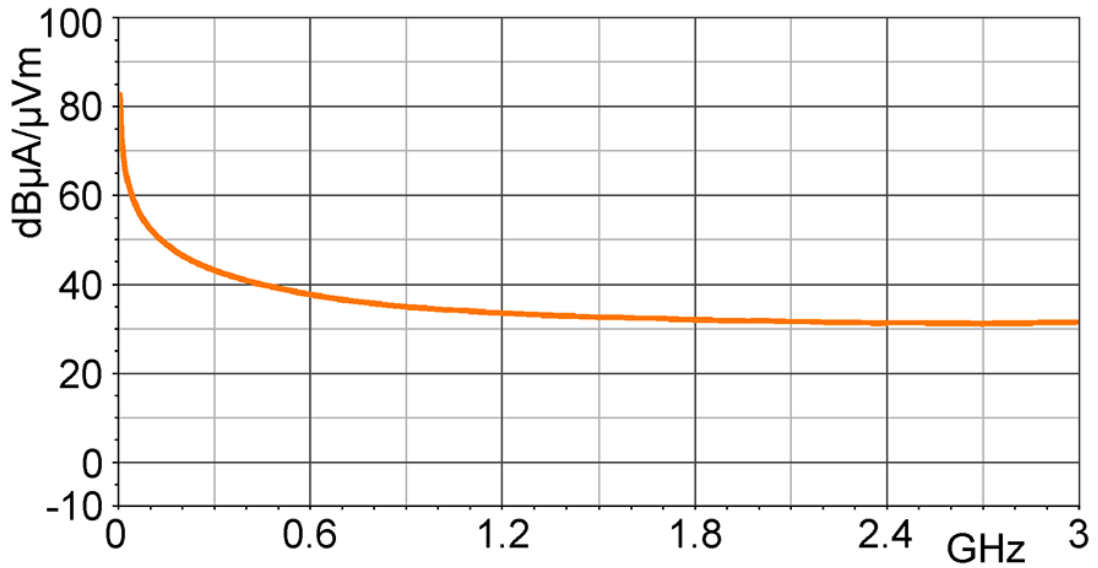
Frequency response [dB $\mu$ V] / [dB $\mu$ A/m]



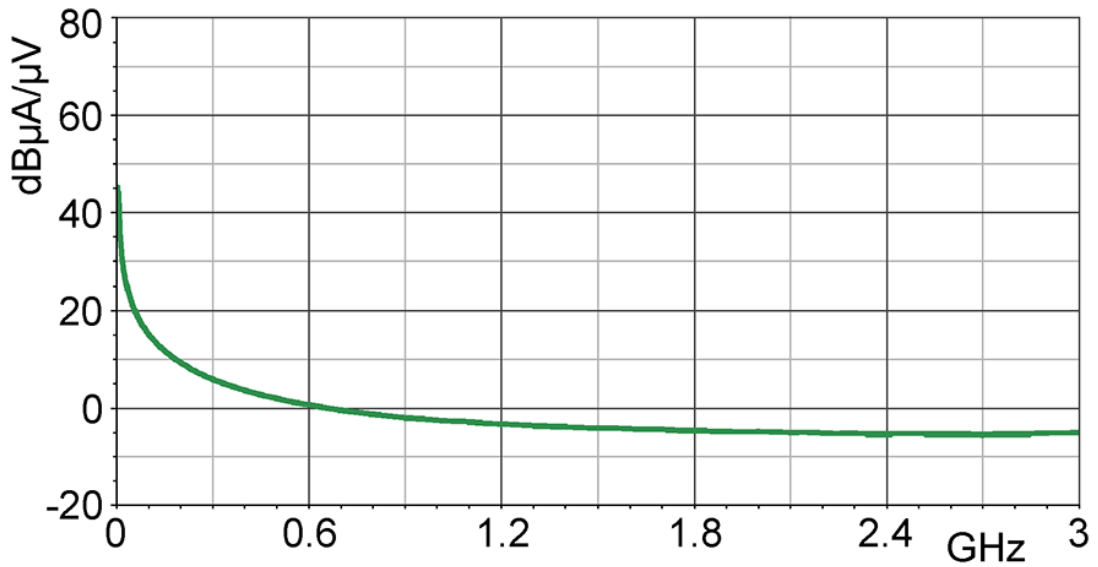
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H-field correction curve [dB $\mu$ A/m] / [dB $\mu$ V]



Current correction curve [dB $\mu$ A] / [dB $\mu$ V]



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## Measuring principles

